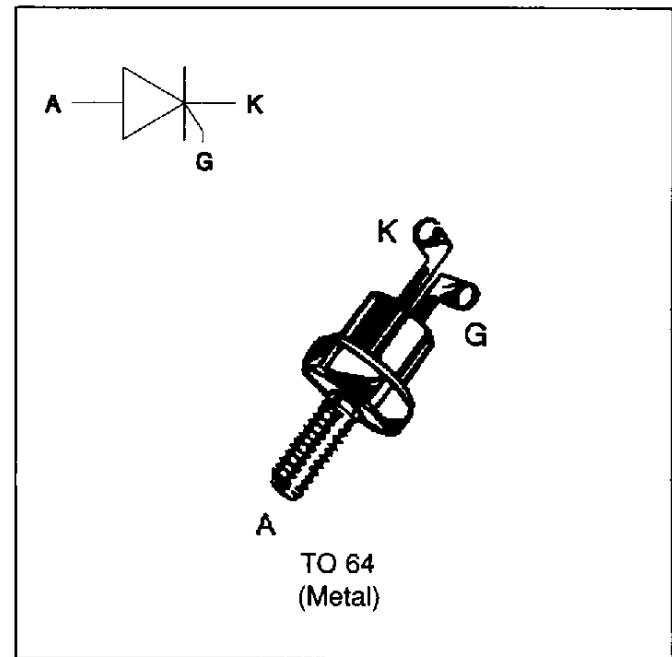


**SCR**
**FEATURES**

- HIGH SURGE CAPABILITY
- HIGH ON-STATE CURRENT
- HIGH STABILITY AND RELIABILITY


**DESCRIPTION**

The 2N 1771 ---> 2N 2619 Family of Silicon Controlled Rectifiers uses a high performance glass passivated technology.

This general purpose Family of Silicon Controlled Rectifiers is designed for power supplies up to 400Hz on resistive or inductive load.

**ABSOLUTE RATINGS (limiting values)**

Symbol	Parameter	Value	Unit
$I_T(\text{RMS})$	RMS on-state current (180° conduction angle)	$T_c = 105^\circ\text{C}$	7.4 A
$I_T(\text{AV})$	Average on-state current (180° conduction angle, single phase circuit)	$T_c = 105^\circ\text{C}$	4.7 A
$I_{TSM}$	Non repetitive surge peak on-state current ( $T_j$ initial = 25°C)	$t_p = 8.3 \text{ ms}$	84 A
		$t_p = 10 \text{ ms}$	80 A
$I^2t$	$I^2t$ value	$t_p = 10 \text{ ms}$	$\text{A}^2\text{s}$
$dI/dt$	Critical rate of rise of on-state current Gate supply : $I_G = 150 \text{ mA}$ $dI_G/dt = 1 \text{ A}/\mu\text{s}$	100	$\text{A}/\mu\text{s}$
$T_{stg}$ $T_j$	Storage and operating junction temperature range	- 40 to + 150	°C
		- 40 to + 125	°C
$T_I$	Maximum lead temperature for soldering during 10 s at 4.5 mm from case	230	°C

Symbol	Parameter	2N					Unit
		1771	1772	1774	1777	2619	
$V_{DRM}$ $V_{RRM}$	Repetitive peak off-state voltage $T_j = 125^\circ\text{C}$	50	100	200	400	600	V

**THERMAL RESISTANCES**

Symbol	Parameter	Value	Unit
R <sub>th</sub> (c-h)	Contact (case to heatsink)	0.4	°C/W
R <sub>th</sub> (j-c) DC	Junction to case for DC	2.5	°C/W

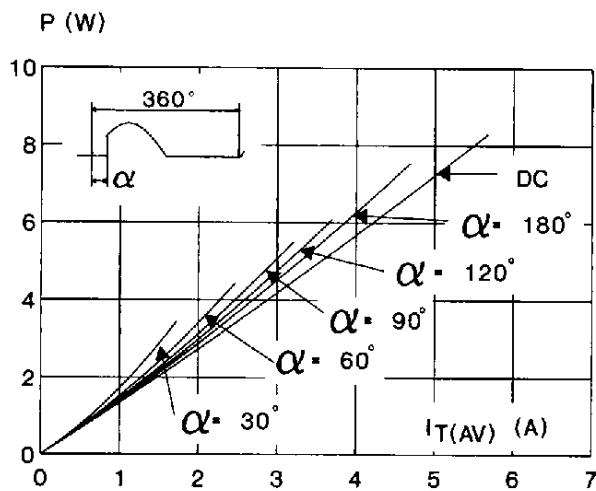
**GATE CHARACTERISTICS (maximum values)**

P<sub>G</sub> (AV) = 1W P<sub>GM</sub> = 20W (tp = 20 μs) I<sub>FGM</sub> = 4A (tp = 20 μs) V<sub>FGM</sub> = 16V (tp = 20 μs) V<sub>RGM</sub> = 5 V.

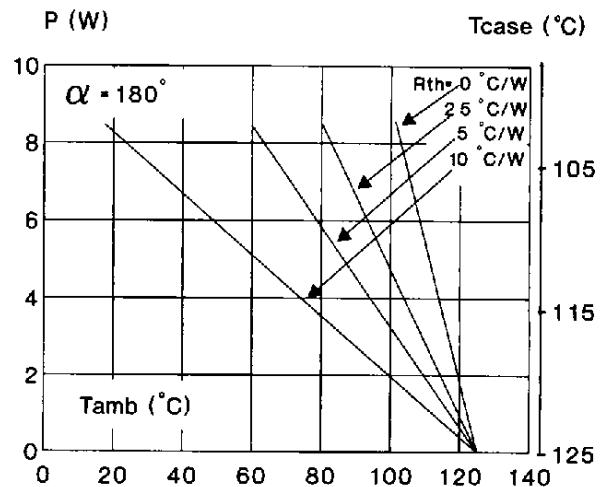
**ELECTRICAL CHARACTERISTICS**

Symbol	Test Conditions			Value	Unit
I <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =33Ω	T <sub>j</sub> =25°C	MAX	15	mA
V <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =33Ω	T <sub>j</sub> =25°C	MAX	1.5	V
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> R <sub>L</sub> =3.3kΩ	T <sub>j</sub> = 125°C	MIN	0.2	V
t <sub>GT</sub>	V <sub>D</sub> =V <sub>DRM</sub> I <sub>G</sub> = 200mA dI <sub>G</sub> /dt = 1.5A/μs	T <sub>j</sub> =25°C	TYP	2	μs
I <sub>L</sub>	I <sub>G</sub> = 1.2 I <sub>GT</sub>	T <sub>j</sub> =25°C	TYP	40	mA
I <sub>H</sub>	I <sub>T</sub> = 100mA gate open	T <sub>j</sub> =25°C	MAX	30	mA
V <sub>TM</sub>	I <sub>TM</sub> = 15A tp= 380μs	T <sub>j</sub> =25°C	MAX	1.85	V
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>DRM</sub> Rated V <sub>RRM</sub> Rated	T <sub>j</sub> =25°C T <sub>j</sub> = 125°C	MAX	0.02 2	mA
dV/dt	Linear slope up to V <sub>D</sub> =67%V <sub>DRM</sub> gate open	T <sub>j</sub> = 125°C	MIN	200	V/μs
T <sub>q</sub>	V <sub>D</sub> =67%V <sub>DRM</sub> I <sub>TM</sub> = 15A V <sub>R</sub> = 24V dI <sub>TM</sub> /dt=30 A/μs dV <sub>D</sub> /dt= 20V/μs	T <sub>j</sub> = 125°C	TYP	70	μs

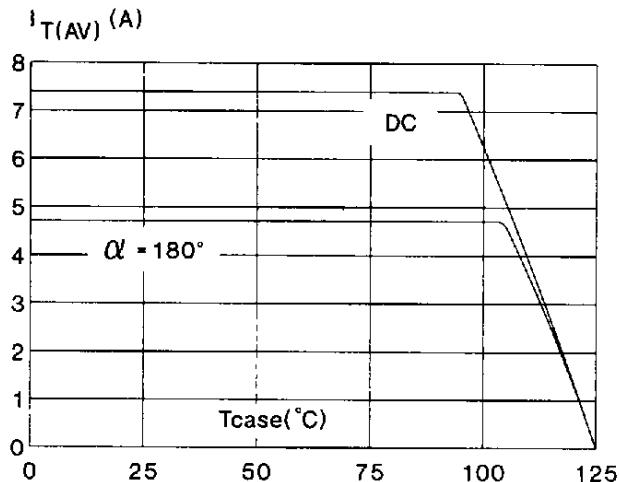
**Fig.1** : Maximum average power dissipation versus average on-state current.



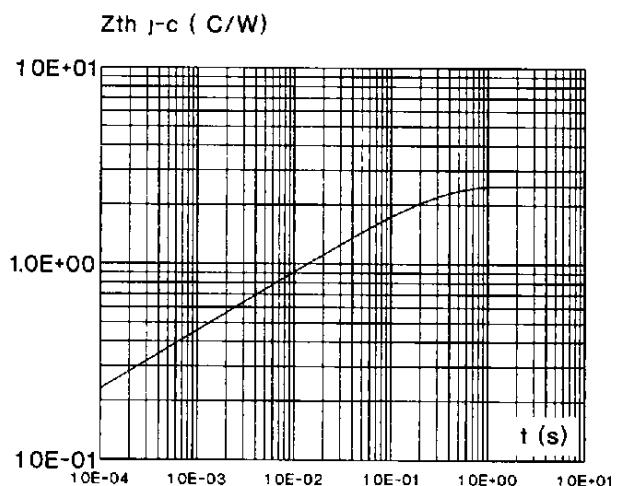
**Fig.2** : Correlation between maximum average power dissipation and maximum allowable temperatures (Tamb and Tcase) for different thermal resistances heatsink + contact.



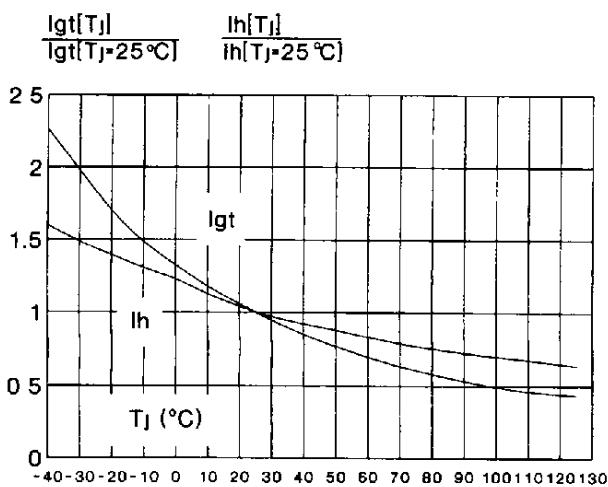
**Fig.3** : Average on-state current versus case temperature.



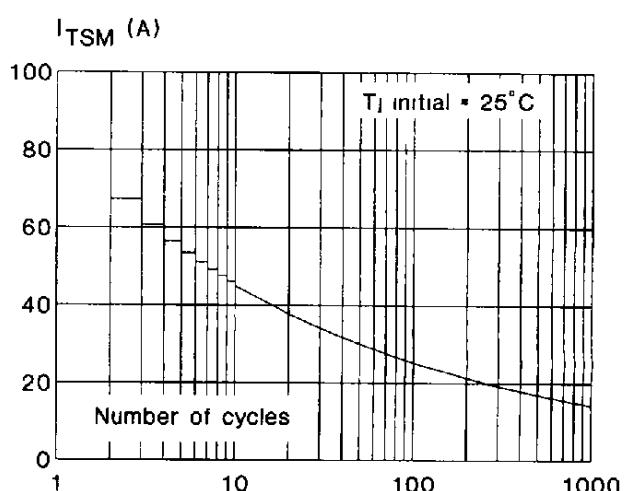
**Fig.4** : Thermal transient impedance junction to ambient versus pulse duration.



**Fig.5** : Relative variation of gate trigger current versus junction temperature.

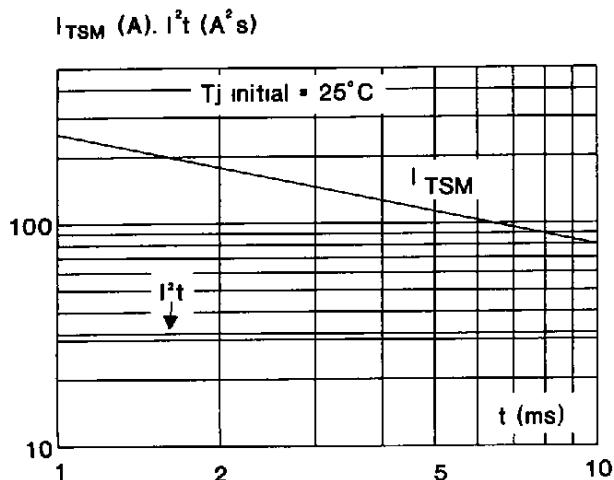


**Fig.6** : Non repetitive surge peak on-state current versus number of cycles.

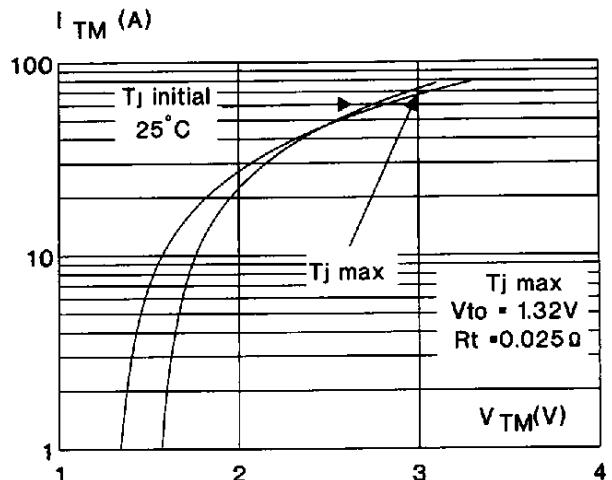


# 2N 1771 ---> 2N 2619

**Fig.7 : Non repetitive surge peak on-state current for a sinusoidal pulse with width :  $t \leq 10$  ms, and corresponding value of  $I^2t$ .**

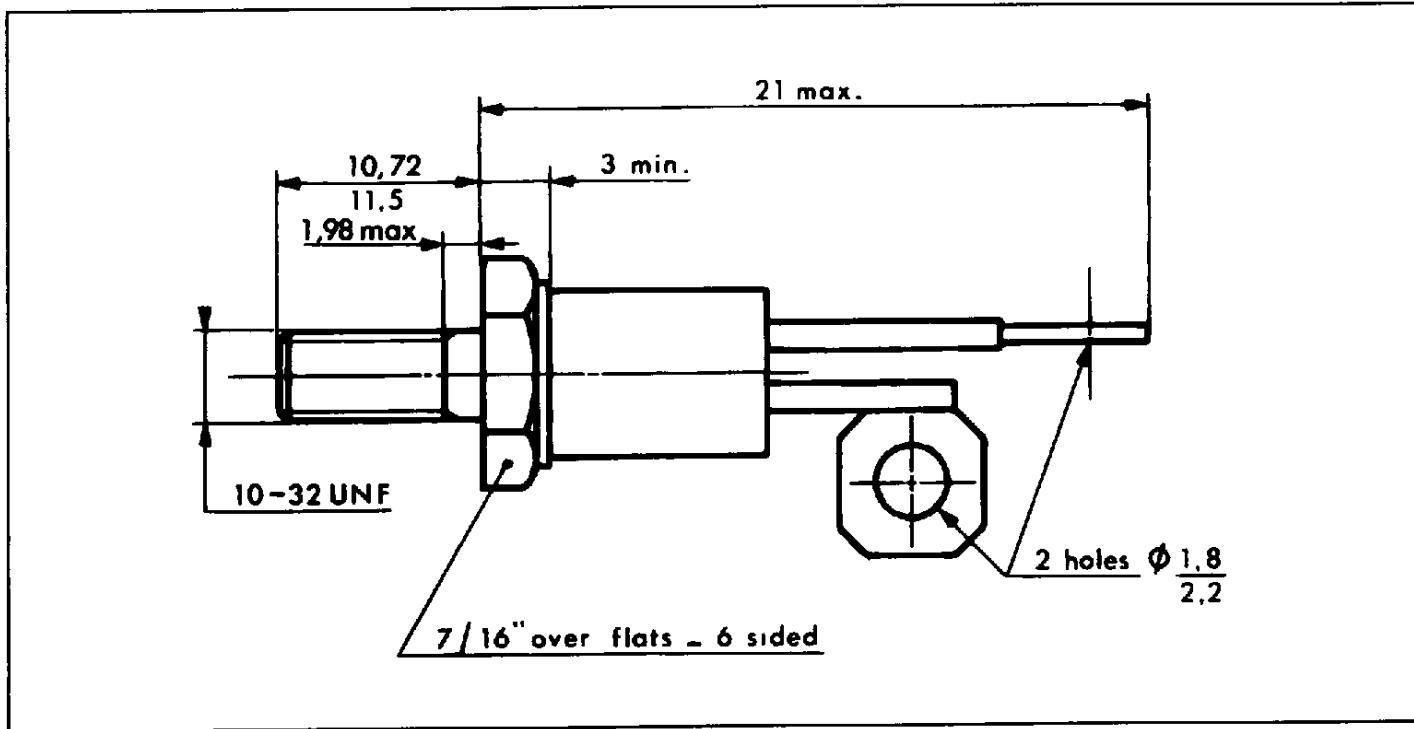


**Fig.8 : On-state characteristics (maximum values).**



## PACKAGE MECHANICAL DATA (in millimeters)

TO 64 Metal



Cooling method : A

Marking : type number

Weight : 5 g

Polarity : Anode (or A2) to case

Stud torque : 3.5 mAN min / 3.8 mAN max